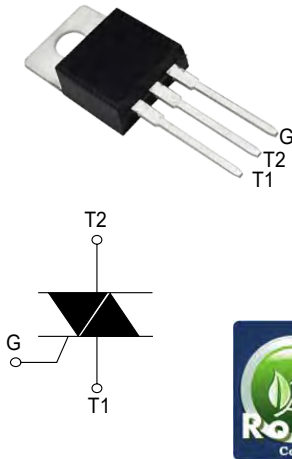
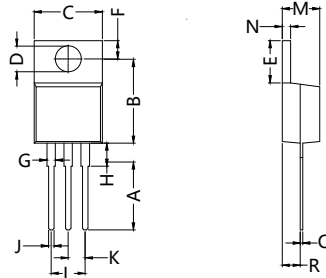


# BTB16

## Discrete Triacs(Non-Isolated)



Dimensions TO-220AB



Dim.	Millimeter	
	Min.	Max.
A	12.70	13.97
B	14.73	16.00
C	9.91	10.66
ØD	3.54	4.08
E	5.85	6.85
F	2.54	3.18
G	1.15	1.65
H	2.79	5.84
J	0.64	1.01
K	2.45BSC	
L	5.05BSC	
M	4.32	4.82
N	1.14	1.39
Q	0.35	0.56
R	2.29	2.79

### ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter			Value	Unit
$I_{T(RMS)}$	RMS on-state current (full sine wave)	TO-220AB	$T_c=100^\circ\text{C}$	16	A
$I_{TSM}$	Non repetitive surge peak on-state current (full cycle, $T_j$ initial= $25^\circ\text{C}$ )	F=60Hz	t=16.7ms	168	A
		F=50Hz	t=20ms	160	
$I^2t$	$I^2t$ Value for fusing	tp=10ms		144	$\text{A}^2\text{s}$
di/dt	Critical rate of rise of on-state current $I_G=2 \times I_{GT}$ , $t_r \leq 100$ ns	F=120Hz	$T_j=125^\circ\text{C}$	50	A/ $\mu\text{s}$
$V_{DSM}/V_{RSM}$	Non repetitive surge peak off-state voltage	tp=10ms	$T_j=25^\circ\text{C}$	$\frac{V_{DRM}}{\sqrt{100}}$	V
$I_{GM}$	Peak gate current	tp=20 $\mu\text{s}$	$T_j=125^\circ\text{C}$	4	A
$P_{G(AV)}$	Average gate power dissipation	$T_j=125^\circ\text{C}$		1	W
$T_{stg}$ $T_j$	Storage junction temperature range Operating junction temperature range			- 40to+150 - 40to+125	$^\circ\text{C}$

### ELECTRICAL CHARACTERISTICS ( $T_j=25^\circ\text{C}$ , unless otherwise specified)

#### ■ SNUBBERLESS™ and LOGIC LEVEL(3Quadrants)

Symbol	Test Conditions	Quadrant		BTB		Unit
				CW	BW	
$I_{GT}(1)$	$V_D=12\text{V}$ $R_L=33\Omega$	I - II - III	MAX.	35	50	mA
$V_{GT}$		I - II - III	MAX.	1.3		V
$V_{GD}$	$V_D=V_{DRM}$ $R_L=3.3\text{k}\Omega$ $T_j=125^\circ\text{C}$	I - II - III	MIN.	0.2		V
$I_H(2)$	$I_T=500$ mA		MAX.	35	50	mA
$I_L$	$I_G=1.2I_{GT}$	I - III	MAX.	50	70	mA
		II		60	80	
dV/dt(2)	$V_D=67\%$ $V_{DRM}$ gate open $T_j=125^\circ\text{C}$		MIN.	500	1000	V/ $\mu\text{s}$
(di/dt)c(2)	Without snubber $T_j=125^\circ\text{C}$		MIN.	8.5	14	A/ms

**Sirectifier®**

# BTB16

## Discrete Triacs(Non-Isolated)

### ■ STANDARD (4 Quadrants)

Symbol	Test Conditions	Quadrant		Value	Unit
$I_{GT}(1)$	$V_D=12V R_L=33\Omega$	I - II - III IV	MAX.	50 100	mA
$V_{GT}$		ALL	MAX.	1.3	V
$V_{GD}$	$V_D = V_{DRM} R_L=3.3\Omega T_j=125^\circ C$	ALL	MIN.	0.2	V
$I_H(2)$	$I_T = 500 \text{ mA}$		MAX.	50	mA
$I_L$	$I_G = 1.2 I_{GT}$	I - III - IV	MAX.	60	mA
		II		120	
$dV/dt(2)$	$V_D = 67\% V_{DRM}$ gate open $T_j = 125^\circ C$		MIN.	400	V/ $\mu s$
$(dV/dt)c(2)$	$(dI/dt)c=7A/ms T_j = 125^\circ C$		MIN.	10	V/ $\mu s$

### STATIC CHARACTERISTICS

Symbol	Test Conditions			Value	Unit
$V_{TM}(2)$	$I_{TM}=5.5A t_p=380\mu s$	$T_j=25^\circ C$	MAX.	1.55	V
$V_{to}(2)$	Threshold voltage	$T_j=125^\circ C$	MAX.	0.85	V
$R_d(2)$	Dynamic resistance	$T_j=125^\circ C$	MAX.	60	m $\Omega$
$I_{DRM}$	$V_{DRM}=V_{RRM}$	$T_j=25^\circ C$	MAX.	5	$\mu A$
$I_{RRM}$		$T_j=125^\circ C$		1	mA

Note 1: minimum IGT is guaranteed at 5% of IGT max.

Note 2: for both polarities of A2 referenced to A1

### THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
$R_{th(j-c)}$	Junction to case(AC)	1.2	$^\circ C/W$
$R_{th(j-a)}$	Junction to ambient	60	$^\circ C/W$

### PRODUCT SELECTOR

Part Number	Voltage (xxx)		Sensitivity	Type	Package
	200 V	~ 1200 V			
BTB16	X	X	50 mA	Standard	TO-220AB

### OTHER INFORMATION

Part Number	Marking	Weight	Base quantity	Packing mode
BTB16	BTB16	2 g	250	Bulk

**Sirectifier**<sup>®</sup>

# BTB16

## Discrete Triacs(Non-Isolated)

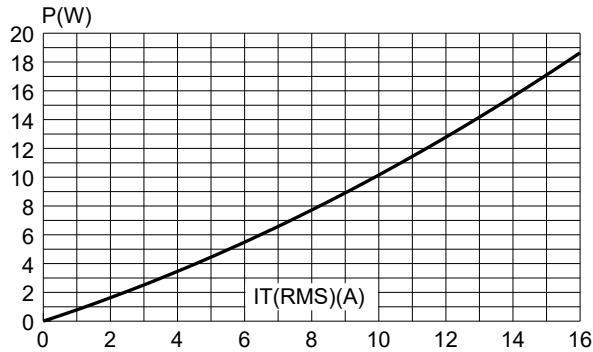


Fig.1:Maximum power dissipation versus RMS on-state current (full cycle).

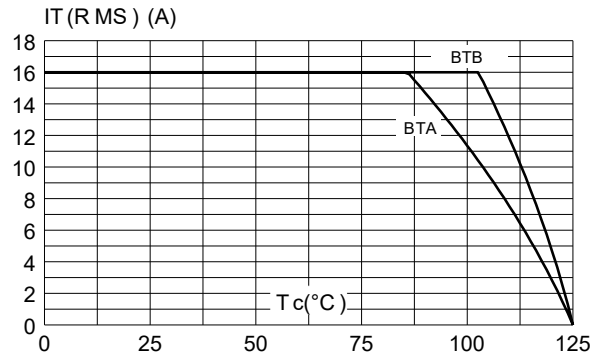


Fig.2:RMS on-state current versus case temperature (full cycle).

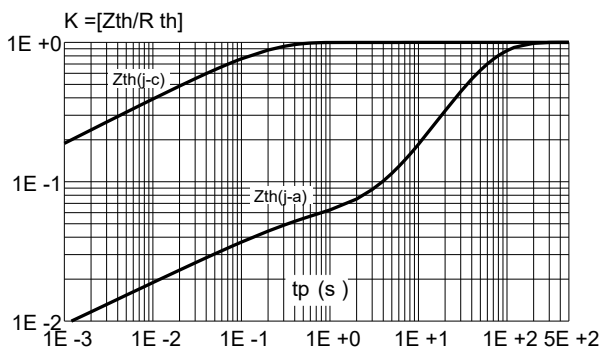


Fig.3:Relative variation of thermal impedance versus pulse duration.

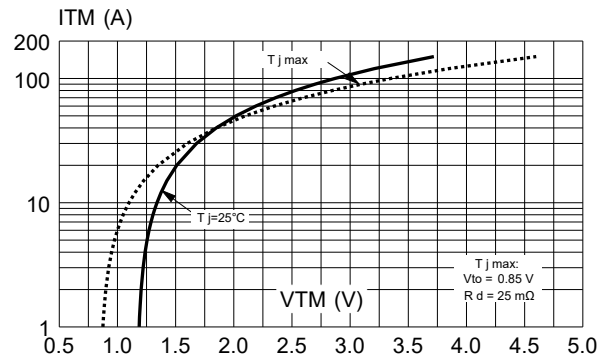


Fig.4:On-state characteristics (maximum values).

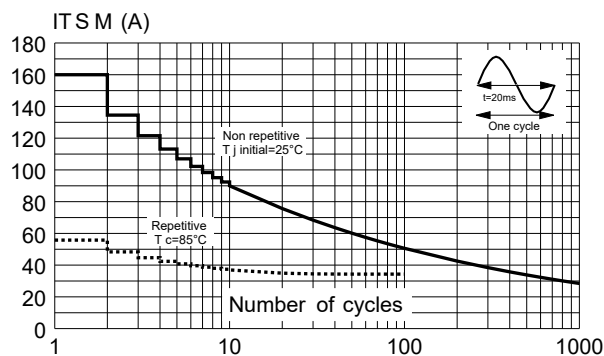


Fig.5:Surge peak on-state current versus number of cycles .

# BTB16

## Discrete Triacs(Non-Isolated)

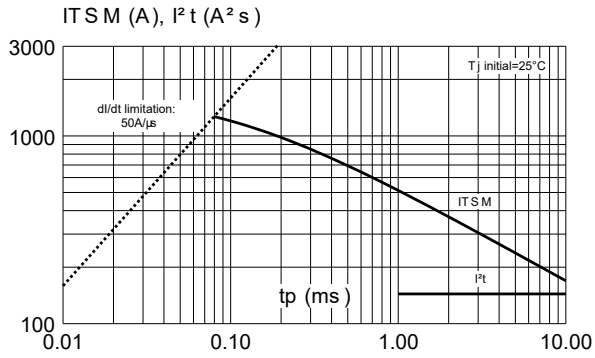


Fig.6: Non-repetitive surge peak on-state current for a sinusoidal pulse with width  $t_p < 10\text{ms}$ , and corresponding value of  $I^2t$ .

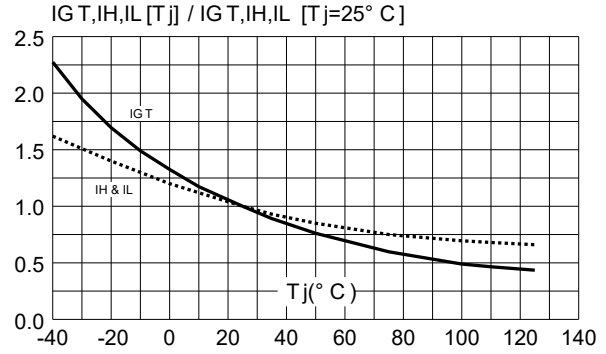


Fig.7: Relative variation of gate trigger current, holding current and latching current versus junction temperature (typical values).

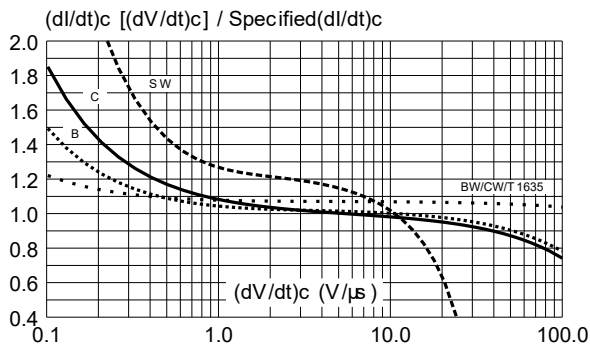


Fig.8: Relative variation of critical rate of decrease of main current versus  $(dV/dt)_c$  (typical values).

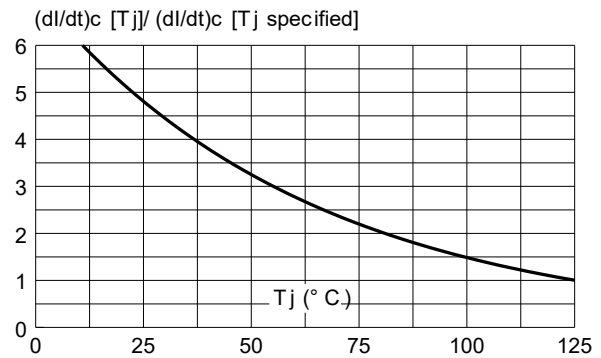


Fig.9: Relative variation of critical rate of decrease of main current versus junction temperature.